

**Search Notes**

Application/Control No.

10/721,549

Examiner

Hien N. Nguyen

Applicant(s)/Patent under  
Reexamination

NAKAMURA ET AL.

Art Unit

2824

**SEARCHED**

Class	Subclass	Date	Examiner
365	171	2/18/2005	HN
	158		
	145		
	173		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
365	171	2/22/2005	HN
	158		
	173		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/18/2005	HN